

## PROBE PIN AND PROBE CARD

## ABSTRACT

A probe pin ( 20 ) includes a low resistance member ( L ) consisting of a first metal with a first conductivity, and a high resistance member ( H ) consisting of a second metal with a second conductivity, the second metal having a resistivity higher than that of the low resistance member ( L ). The probe pin has a multi layered part ( T5, T505, T603 ) between a contact part ( 20c ) and a terminal part ( 20t ), where the multi layered part is configured in the order of the high resistance member ( H ), a slit ( S ) of air gap, and the low resistance member ( L ), in a first direction ( Y ) different from a buckling direction of the probe pin ( 20 ) at the time of inspection of a test object ( W ). The low resistance member ( L ) and the high resistance member ( H ) are arranged so as not to overlap with each other, when the multi layered part ( T5, T505, T603 ) is viewed from the buckling direction ( Z ).

Figure 2